## NB4N527S

# 3.3V, 2.5Gb/s Dual AnyLevel ${ }^{\mathrm{TM}}$ to LVDS Receiver/Driver/Buffer/ Translator with Internal Input Termination 

NB4N527S is a clock or data Receiver/Driver/Buffer/Translator capable of translating AnyLevel ${ }^{\mathrm{TM}}$ input signal (LVPECL, CML, HSTL, LVDS, or LVTTL/LVCMOS) to LVDS. Depending on the distance, noise immunity of the system design, and transmission line media, this device will receive, drive or translate data or clock signals up to $2.5 \mathrm{~Gb} / \mathrm{s}$ or 1.5 GHz , respectively.

The NB4N527S has a wide input common mode range of GND +50 mV to $\mathrm{V}_{\mathrm{CC}}-50 \mathrm{mV}$ combined with two $50 \Omega$ internal termination resistors is ideal for translating differential or single-ended data or clock signals to 350 mV typical LVDS output levels without use of any additional external components (Figure 6).

The device is offered in a small $3 \mathrm{~mm} \times 3 \mathrm{~mm}$ QFN-16 package. NB4N527S is targeted for data, wireless and telecom applications as well as high speed logic interface where jitter and package size are main requirements. Application notes, models, and support documentation are available on www.onsemi.com.

- Maximum Input Clock Frequency up to 1.5 GHz
- Maximum Input Data Rate up to $2.5 \mathrm{~Gb} / \mathrm{s}$ (Figure 5)
- 470 ps Maximum Propagation Delay
- 1 ps Maximum RMS Jitter
- 140 ps Maximum Rise/Fall Times
- Single Power Supply; $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V} \pm 10 \%$
- Temperature Compensated TIA/EIA-644 Compliant LVDS Outputs
- Internal $50 \Omega$ Termination Resistor per Input Pin
- GND +50 mV to $\mathrm{V}_{\mathrm{CC}}-50 \mathrm{mV} \mathrm{V}_{\mathrm{CMR}}$ Range
- These are $\mathrm{Pb}-$ Free Devices


Figure 2. Typical Output Waveform at $2.488 \mathrm{~Gb} / \mathrm{s}$ with PRBS $\mathbf{2 ~}^{23-1}$ (VINPP $=400 \mathrm{mV}$; Input Signal DDJ = $\mathbf{1 4} \mathrm{ps}$ )

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(Note: Microdot may be in either location)
*For additional marking information, refer to Application Note AND8002/D.


Figure 1. Functional Block Diagram $*_{\mathrm{T}}{ }_{\text {TN }}$

## ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 9 of this data sheet.

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Figure 3. Pin Configuration (Top View)

Table 1. PIN DESCRIPTION

| Pin | Name | 1/0 | Description |
| :---: | :---: | :---: | :---: |
| 1 | VTD1 | - | Internal $50 \Omega$ termination pin for D1. ( $\mathrm{R}_{\text {TIN }}$ ) |
| 2 | D1 | LVPECL, CML, LVDS, LVCMOS, LVTTL, HSTL | Noninverted differential clock/data D1 input (Note 1). |
| 3 | D1 | LVPECL, CML, LVDS, LVCMOS, LVTTL, HSTL | Inverted differential clock/data $\overline{\text { D1 }}$ input (Note 1). |
| 4 | VTD1 | - | Internal $50 \Omega$ termination pin for $\overline{\mathrm{D} 1 .}$ ( $\mathrm{R}_{\text {TIN }}$ ) |
| 5 | GND | - | 0 V . Ground. |
| 6, 7 | NC |  | No connect. |
| 8 | $\mathrm{V}_{\mathrm{CC}}$ |  | Positive Supply Voltage. |
| 9 | Q1 | LVDS Output | Inverted D1 output. Typically loaded with $100 \Omega$ receiver termination resistor across differential pair. |
| 10 | Q1 | LVDS Output | Noninverted D1 output. Typically loaded with $100 \Omega$ receiver termination resistor across differential pair. |
| 11 | $\overline{\text { Q0 }}$ | LVDS Output | Inverted DO output. Typically loaded with $100 \Omega$ receiver termination resistor across differential pair. |
| 12 | Q0 | LVDS Output | Noninverted DO output. Typically loaded with $100 \Omega$ receiver termination resistor across differential pair. |
| 13 | VTD0 | - | Internal $50 \Omega$ termination pin for DO. |
| 14 | D0 | LVPECL, CML, LVDS, LVCMOS, LVTTL, HSTL | Noninverted differential clock/data D0 input (Note 1). |
| 15 | D0 | LVPECL, CML, LVDS, LVCMOS, LVTTL, HSTL | Inverted differential clock/data $\overline{\text { DO }}$ input (Note 1). |
| 16 | VTDO | - | Internal $50 \Omega$ termination pin for $\overline{\mathrm{DO}}$. |
| EP |  |  | Exposed pad. EP on the package bottom is thermally connected to the die improved heat transfer out of package. The pad is not electrically connected to the die, but is recommended to be soldered to GND on the PCB. |

1. In the differential configuration when the input termination pins(VTDO/VTDO, VTD1/VTD1) are connected to a common termination voltage or left open, and if no signal is applied on D0/D0, D1/D1 input, then the device will be susceptible to self-oscillation.

## NB4N527S

Table 2. ATTRIBUTES

| Characteristics | Value |  |
| :--- | ---: | :---: |
| Moisture Sensitivity (Note 2) | Level 1 |  |
| Flammability Rating | Oxygen Index: 28 to 34 | UL 94 V-0 @ 0.125 in |
| ESD ProtectionHuman Body Model <br> Machine Model <br> Charged Device Model | $>2 \mathrm{kV}$ <br> $>200 \mathrm{~V}$ <br> $>1 \mathrm{kV}$ |  |
| Transistor Count |  |  |
| Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test |  |  |

2. For additional information, see Application Note AND8003/D.

Table 3. MAXIMUM RATINGS

| Symbol | Parameter | Condition 1 | Condition 2 | Rating | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {CC }}$ | Positive Power Supply | GND $=0 \mathrm{~V}$ |  | 3.8 | V |
| $\mathrm{V}_{1}$ | Positive Input | GND $=0 \mathrm{~V}$ | $\mathrm{V}_{1}=\mathrm{V}_{\text {cc }}$ | 3.8 | V |
| $\mathrm{I}_{\mathrm{N}}$ | Input Current Through $\mathrm{R}_{\mathrm{T}}(50 \Omega$ Resistor) | Static Surge |  | $\begin{aligned} & 35 \\ & 70 \end{aligned}$ | $\begin{aligned} & \mathrm{mA} \\ & \mathrm{~mA} \end{aligned}$ |
| Iosc | Output Short Circuit Current Line-to-Line ( Q to $\overline{\mathrm{Q}}$ ) Line-to-End ( Q or $\overline{\mathrm{Q}}$ to GND) | $\begin{aligned} & \mathrm{Q} \text { or } \overline{\mathrm{Q}} \text { to } \mathrm{GND} \\ & \mathrm{Q} \text { to } \overline{\mathrm{Q}} \end{aligned}$ | Continuous Continuous | $\begin{aligned} & 12 \\ & 24 \end{aligned}$ | mA |
| $\mathrm{T}_{\text {A }}$ | Operating Temperature Range | QFN-16 |  | -40 to +85 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {stg }}$ | Storage Temperature Range |  |  | -65 to +150 | ${ }^{\circ} \mathrm{C}$ |
| $\theta_{\mathrm{JA}}$ | Thermal Resistance (Junction-to-Ambient) (Note 3) | $\begin{aligned} & 0 \text { lfpm } \\ & 500 \text { lfpm } \end{aligned}$ | $\begin{aligned} & \text { QFN-16 } \\ & \text { QFN-16 } \end{aligned}$ | $\begin{aligned} & 41.6 \\ & 35.2 \end{aligned}$ | $\begin{aligned} & { }^{\circ} \mathrm{C} / \mathrm{W} \\ & { }^{\circ} \mathrm{C} / \mathrm{W} \end{aligned}$ |
| $\theta_{\text {Jc }}$ | Thermal Resistance (Junction-to-Case) | 1S2P (Note 3) | QFN-16 | 4.0 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\mathrm{T}_{\text {sol }}$ | Wave SolderPb <br> $\mathrm{Pb}-\mathrm{Free}$ |  |  | $\begin{aligned} & 265 \\ & 265 \end{aligned}$ | ${ }^{\circ} \mathrm{C}$ |

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.
3. JEDEC standard multilayer board - 1S2P (1 signal, 2 power) with 8 filled thermal vias under exposed pad.

Table 4. DC CHARACTERISTICS, CLOCK INPUTS, LVDS OUTPUTS $\mathrm{V}_{C C}=3.0 \mathrm{~V}$ to $3.6 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$

| Symbol | Characteristic | Min | Typ | Max | Unit |
| :--- | :--- | :---: | :---: | :---: | :---: |
| $I_{\text {CC }}$ | Power Supply Current (Note 8) |  | 40 | 53 | mA |

DIFFERENTIAL INPUTS DRIVEN SINGLE-ENDED (Figures 11, 12, 16, and 18)

| $\mathrm{V}_{\mathrm{th}}$ | Input Threshold Reference Voltage Range (Note 7) | GND +100 | $\mathrm{~V}_{\mathrm{CC}}-100$ | mV |  |
| :--- | :--- | :--- | :--- | :---: | :---: |
| $\mathrm{V}_{\mathrm{IH}}$ | Single-ended Input HIGH Voltage | $\mathrm{V}_{\mathrm{th}}+100$ |  | $\mathrm{~V}_{\mathrm{CC}}$ | mV |
| $\mathrm{V}_{\mathrm{IL}}$ | Single-ended Input LOW Voltage | GND |  | $\mathrm{V}_{\mathrm{th}}-100$ | mV |

DIFFERENTIAL INPUTS DRIVEN DIFFERENTIALLY (Figures 7, 8, 9, 10, 17, and 19)

| $\mathrm{V}_{\text {IHD }}$ | Differential Input HIGH Voltage | 100 |  | $\mathrm{~V}_{\mathrm{CC}}$ | mV |
| :--- | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {ILD }}$ | Differential Input LOW Voltage | GND |  | $\mathrm{V}_{\mathrm{CC}}-100$ | mV |
| $\mathrm{V}_{\mathrm{CMR}}$ | Input Common Mode Range (Differential Configuration) | $\mathrm{GND}+50$ |  | $\mathrm{~V}_{\mathrm{CC}}-50$ | mV |
| $\mathrm{V}_{\text {ID }}$ | Differential Input Voltage ( $\left.\mathrm{V}_{\text {IHD }}-\mathrm{V}_{\text {ILD }}\right)$ | 100 |  | $\mathrm{~V}_{\mathrm{CC}}$ | mV |
| $\mathrm{R}_{\text {TIN }}$ | Internal Input Termination Resistor | 40 | 50 | 60 | $\Omega$ |

LVDS OUTPUTS (Note 4)

| $\mathrm{V}_{\mathrm{OD}}$ | Differential Output Voltage | 250 |  | 450 | mV |
| :--- | :--- | :---: | :---: | :---: | :---: |
| $\Delta \mathrm{V}_{\mathrm{OD}}$ | Change in Magnitude of $\mathrm{V}_{\mathrm{OD}}$ for Complementary Output States (Note 9) | 0 | 1 | 25 | mV |
| $\mathrm{V}_{\mathrm{OS}}$ | Offset Voltage (Figure 15) | 1125 |  | 1375 | mV |
| $\Delta \mathrm{V}_{\mathrm{OS}}$ | Change in Magnitude of $\mathrm{V}_{\mathrm{OS}}$ for Complementary Output States (Note 9) | 0 | 1 | 25 | mV |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage (Note 5) |  | 1425 | 1600 | mV |
| $\mathrm{V}_{\mathrm{OL}}$ | Output LOW Voltage (Note 6) | 900 | 1075 |  | mV |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.
4. LVDS outputs require $100 \Omega$ receiver termination resistor between differential pair. See Figure 14.
5. $\mathrm{V}_{\mathrm{OH}} \max =\mathrm{V}_{\mathrm{OS}} \max +1 / 2 \mathrm{~V}_{\mathrm{OD}} \max$.
6. $\mathrm{V}_{\text {OL }} \max =\mathrm{V}_{\text {OS }} \min -1 / 2 \mathrm{~V}_{\text {OD }} \max$.
7. $V_{\text {th }}$ is applied to the complementary input when operating in single-ended mode.
8. Input termination pins open, $D x / D x$ at the $D C$ level within $V_{C M R}$ and output pins loaded with $R_{L}=100 \Omega$ across differential.
9. Parameter guaranteed by design verification not tested in production.

Table 5. AC CHARACTERISTICS $\mathrm{V}_{\mathrm{CC}}=3.0 \mathrm{~V}$ to 3.6 V , $\mathrm{GND}=0 \mathrm{~V}$; (Note 10)

| Symbol | Characteristic | $-40^{\circ} \mathrm{C}$ |  |  | $25^{\circ} \mathrm{C}$ |  |  | $85^{\circ} \mathrm{C}$ |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| V ${ }_{\text {OUTPP }}$ | Output Voltage Amplitude (@ $\left.V_{\text {INPPmin }}\right) f_{i n} \leq 1.0 \mathrm{GHz}$ (Figure 4) | $\begin{aligned} & \hline 220 \\ & 200 \end{aligned}$ | $\begin{aligned} & 350 \\ & 300 \end{aligned}$ |  | $\begin{aligned} & 220 \\ & 200 \end{aligned}$ | $\begin{aligned} & 350 \\ & 300 \end{aligned}$ |  | $\begin{aligned} & 220 \\ & 200 \end{aligned}$ | $\begin{aligned} & 350 \\ & 300 \end{aligned}$ |  | mV |
| $\mathrm{f}_{\text {DATA }}$ | Maximum Operating Data Rate | 1.5 | 2.5 |  | 1.5 | 2.5 |  | 1.5 | 2.5 |  | Gb/s |
| $\mathrm{t}_{\text {PLH }}$, $t_{\text {PHL }}$ | Differential Input to Differential Output Propagation Delay | 270 | 370 | 470 | 270 | 370 | 470 | 270 | 370 | 470 | ps |
| tskew | Duty Cycle Skew (Note 11) Within Device Skew (Note 17) Device-to-Device Skew (Note 15) |  | $\begin{gathered} 8 \\ 5 \\ 30 \end{gathered}$ | $\begin{gathered} 45 \\ 25 \\ 100 \end{gathered}$ |  | $\begin{gathered} 8 \\ 5 \\ 30 \end{gathered}$ | $\begin{gathered} \hline 45 \\ 25 \\ 100 \end{gathered}$ |  | 8 5 30 | $\begin{gathered} 45 \\ 25 \\ 100 \end{gathered}$ | ps |
| $\mathrm{t}_{\text {JITTER }}$ |  |  | $\begin{gathered} \hline 0.5 \\ 0.5 \\ 6 \\ 7 \\ 10 \\ 20 \end{gathered}$ | $\begin{gathered} 1 \\ 1 \\ 10 \\ 20 \\ 20 \\ 25 \\ 40 \end{gathered}$ |  | $\begin{gathered} \hline 0.5 \\ 0.5 \\ 6 \\ 7 \\ 10 \\ 20 \end{gathered}$ | $\begin{gathered} 1 \\ 1 \\ 10 \\ 20 \\ 20 \\ 25 \\ 40 \end{gathered}$ |  | $\begin{gathered} \hline 0.5 \\ 0.5 \\ 6 \\ 7 \\ 10 \\ 20 \end{gathered}$ | $\begin{gathered} 1 \\ 1 \\ 10 \\ 20 \\ 20 \\ 25 \\ 40 \end{gathered}$ | ps |
| $\mathrm{V}_{\text {INPP }}$ | Input Voltage Swing/Sensitivity (Differential Configuration) (Note 12) | 100 |  | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}-1 \\ & \mathrm{GND} \end{aligned}$ | 100 |  | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}- \\ & \mathrm{GND} \end{aligned}$ | 100 |  | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}- \\ & \mathrm{GND} \end{aligned}$ | mV |
| $\begin{array}{\|l\|l} \hline t_{r} \\ t_{f} \end{array}$ | $\begin{aligned} & \begin{array}{l} \text { Output Rise/Fall Times @ } 250 \mathrm{MHz} \\ (20 \%-80 \%) \end{array} \quad \text { Q, } \overline{\mathrm{Q}} \end{aligned}$ | 60 | 100 | 140 | 60 | 100 | 140 | 60 | 100 | 140 | ps |

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 Ifpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.
10. Measured by forcing $V_{\text {INPPmin }}$ with $50 \%$ duty cycle clock source and $V_{C C}-1400 \mathrm{mV}$ offset. All loading with an external $R_{L}=100 \Omega$ across " D " and " D " of the receiver. Input edge rates $150 \mathrm{ps}(20 \%-80 \%)$.
11. See Figure 13 differential measurement of $t_{\text {skew }}=\left|t_{\text {PLH }}-t_{\text {PHL }}\right|$ for a nominal $50 \%$ differential clock input waveform @ 250 MHz .
12. Input voltage swing is a single-ended measurement operating in differential mode.
13. RMS jitter with $50 \%$ duty cycle input clock signal.
14. Deterministic jitter with input NRZ data at PRBS $2^{23}-1$ and K28.5.
15. Skew is measured between outputs under identical transition @ 250 MHz .
16. Crosstalk induced jitter is the additive deterministic jitter to channel one with channel two active both running at $622 \mathrm{~Gb} / \mathrm{s} \operatorname{PRBS} 2^{23}-1$ as an asynchronous signals.
17. The worst case condition between $\mathrm{Q} 0 / \mathrm{Q0}$ and $\mathrm{Q} 1 / \mathrm{Q1}$ from either $\mathrm{DO} / \overline{\mathrm{DO}}$ or $\mathrm{D} 1 / \overline{\mathrm{D} 1}$, when both outputs have the same transition.


Figure 4. Output Voltage Amplitude ( $\mathrm{V}_{\text {OUTPP }}$ ) versus Input Clock Frequency ( $\mathrm{f}_{\mathrm{in}}$ ) and Temperature ( $@ \mathrm{~V}_{\mathrm{CC}}=3.3 \mathrm{~V}$ )

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Figure 5. Typical Output Waveform at $2.488 \mathrm{~Gb} / \mathrm{s}$ with PRBS $\mathbf{2}^{23-1}$ and OC48 mask ( $\mathrm{V}_{\text {INPP }}=100 \mathrm{mV}$; Input Signal DDJ = $\mathbf{1 4} \mathrm{ps}$ )


Figure 6. Input Structure


Figure 7. LVPECL Interface


Figure 9. Standard $50 \Omega$ Load CML Interface


Figure 8. LVDS Interface


Figure 10. HSTL Interface


Figure 11. LVCMOS Interface
${ }^{*} \mathrm{R}_{\text {TIN }}$, Internal Input Termination Resistor.


Figure 12. LVTTL Interface


Figure 13. AC Reference Measurement


Figure 14. Typical LVDS Termination for Output Driver and Device Evaluation


Figure 15. LVDS Output

D


Figure 16. Differential Input Driven Single-Ended


Figure 17. Differential Inputs Driven Differentially


Figure 18. $\mathrm{V}_{\text {th }}$ Diagram


Figure 19. $\mathrm{V}_{\mathrm{CMR}}$ Diagram

## NB4N527S

## ORDERING INFORMATION

| Device | Package | Shipping $^{\dagger}$ |
| :--- | :---: | :---: |
| NB4N527SMNG | QFN-16 <br> (Pb-Free) | 123 Units / Rail |
| NB4N527SMNR2G | QFN-16 <br> (Pb-Free) | $3000 /$ Tape \& Reel |

$\dagger$ For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## PACKAGE DIMENSIONS

QFN16 3x3, 0.5P
CASE 485G-01
ISSUE E



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL.
4. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

| DIM | MILLIMETERS |  |
| :---: | :---: | :---: |
|  | MIN | MAX |
| A | 0.80 | 1.00 |
| A1 | 0.00 | 0.05 |
| A3 | 0.20 REF |  |
| b | 0.18 | 0.30 |
| D | 3.00 BSC |  |
| D2 | 1.65 | 1.85 |
| E | 3.00 BSC |  |
| E2 | 1.65 | 1.85 |
| e | 0.50 BSC |  |
| K | 0.18 TYP |  |
| L | 0.30 | 0.50 |
| L1 | 0.00 | 0.15 |

RECOMMENDED


DIMENSIONS: MILLIMETERS
*For additional information on our $\mathrm{Pb}-$ Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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